

Conference Agenda

Session

SES-09: Material Characterization II

Time: Friday, 07/Feb/2025: 9:00am - 10:40am

Session Chair: Johann Christopher Engster

Session Chair: Jingsong Lin

Presentations

Sparse-view Material Decomposition for Spectral X-ray CT using Neural Radiance Fields

Takumi Hotta^{1,4}, Tatsuya Yatagawa², Yutaka Otake¹, Toru Aoki^{3,5}

¹The University of Tokyo; ²Hitotsubashi University; ³Shizuoka University; ⁴Zodiac Co., Ltd.; ⁵ANSeeN Inc.

Volumetric sub- μ -CT imaging for forensic wood identification

Jannik Stebani^{1,2}, Tim Lewandrowski³, Kilian Dremel¹, Simon Zabler^{1,4}, Volker Haag³

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Determination of the image quality in computed tomography and its standardisation

Anne-Françoise Obaton¹, Uwe Ewert², Holger Roth³, Janka Wilbig¹, Clément Remacha⁴, Nicolas Cochennec⁴, Lionel Gay⁴, Marko Katic⁵

¹Laboratoire National de Métrologie et d'Essais (LNE), France; ²Kowotest GmbH, Germany; ³Waygate Technologies, Baker Hughes, Germany; ⁴Safran Tech, France; ⁵University of Zagreb, Croatia

Single X-ray Projection Material Decomposition using a Mesh Projector

Fleur Linsen¹, Domenico Iuso^{1,2}, Jan Sijbers^{1,2}

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Assessment of the variability of unidirectional preprints at multiple scales

Silvia Gomarasca¹, Amin Hosseini¹, Ran Tao¹, Daniel Peeters¹, Bilim Atli-Veltin¹, Clemens Dransfeld¹, Benedikt Boos², Christoph Queck², Martin Gurka²

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